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Refereed Congress / Symposium Publications in Proceedings

I. **Defect Classification from Electronic Card Images by Deep Learning Elektronik Kart Görüntülerinden Derin Öğrenme ile Kusur Siniflandirmasi**
Eryilmaz M., Cil M., Akturk S., Tilegi M., Tirak H., YILMAZ A., Yuksel S. E., GÖKCEN D.
30th Signal Processing and Communications Applications Conference, SIU 2022, Safranbolu, Turkey, 15 - 18 May 2022

Metrics

Publication: 1